



2816

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Abijit Jas et al.

Title: LINEAR FEEDBACK SHIFT REGISTER RESEEDING

Docket No.: 884.911US1

Serial No.: 10/666169

Filed: September 19, 2003

Due Date: N/A

Examiner: Unknown

Group Art Unit: 2816

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

We are transmitting herewith the following attached items (as indicated with an "X"):

☒ A return postcard.

☒ A Supplemental Information Disclosure Statement (1 pgs.), Form 1449 (1 pg.), and copies of 16 cited documents.

If not provided for in a separate paper filed herewith, Please consider this a PETITION FOR EXTENSION OF TIME for sufficient number of months to enter these papers and please charge any additional fees or credit overpayment to Deposit Account No. 19-0743.

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

Customer Number 21186

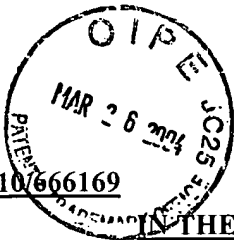
By: David R. Cochran
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Reg. No. 46,632
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CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 22 day of March, 2004.

Chris Hammond
Name

Chris Hammond
Signature

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.
(GENERAL)



S/N 10/666169

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant:	Abhijit Jas et al.	Examiner:	Unknown
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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Supplemental Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Supplemental Information Disclosure Statement. However, if an Office Action on the merits has been mailed, the Commissioner is hereby authorized to charge the required fees to Deposit Account No. 19-0743 in order to have this Supplemental Information Disclosure Statement considered.

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.

Respectfully submitted,

ABHIJIT JAS ET AL.

By their Representatives,

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Date 19 March 2004

By David R. Cochran
David R. Cochran
Reg. No. 46,632

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Chris Hammond
Name

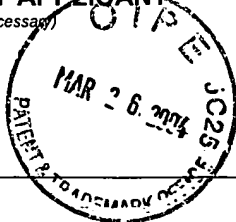
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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)



Complete if Known

Application Number	10/666169
Filing Date	September 19, 2003
First Named Inventor	Jas, Abhijit
Group Art Unit	2816
Examiner Name	Unknown

Sheet 1 of 1

Attorney Docket No: 884.911US1

US PATENT DOCUMENTS

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	Filing Date If Appropriate
	US-6,032,278	02/29/2000	Parvathala, Praveen , et al.	714	726	12/26/1996
	US-6,477,674	11/05/2002	Bates, Sarah E., et al.	714	738	11/05/2002
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	US-6,564,347	05/13/2003	Mates, John W.	714	727	07/29/1999

FOREIGN PATENT DOCUMENTS

Examiner Initials *	Foreign Document No	Publication Date	Name of Patentee or Applicant of cited Document	Class	Subclass	T ²
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OTHER DOCUMENTS -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
		"Linear Feedback Shift Registers", www.math.cudenver.edu/~wcherow/courses/m5410/m5410fsr.html , 1-8	
		"What's an LFSR?", Texas Instruments SCTA036A, (12/01/1996), 11 pgs.	
		AL-YAMANI, AHMAD A., et al., "Built-In Reseeding For Serial Bist", <u>Proceedings 21st IEEE VLSI Test Symposium</u> , (2002), 1-22	
		BAYRAKTAROGLU, ISMET , et al., "Test volume and application time reduction through scan chain concealment", <u>Proceedings of the 38th Design Automation Conference</u> , (2001), 151-5	
		HELLEBRAND, SYBILLE , "A Mixed Mode Bist Scheme Based on Reseeding of Folding Counters", <u>Proceedings International Test Conference 2000</u> , (2000), 778-84	
		JAS, ABHIJIT , et al., "An Embedded Core DFT Scheme to Obtain Highly Compressed Test Sets", <u>Test Symposium</u> , 1999. (ATS '99) <u>Proceedings. Eighth Asian</u> , 16-18 Nov. 1999, (1999), 275-280	
		JAS, ABHIJIT , et al., "Scan vector compression/decompression using statistical coding", <u>VLSI Test Symposium</u> , 1999. <u>Proceedings. 17th IEEE</u> , 25-29 April 1999, (1999), 114-120	
		JAS, ABHIJIT , et al., "Test vector decompression via cyclical scan chains and its application to testing core-based designs", <u>Test Conference</u> , 1998. <u>Proceedings. International</u> , 18-23 Oct. 1998, (1998), 458-464	
		JAS, ABHIJIT , "Virtual scan chains: a means for reducing scan length in cores", <u>VLSI Test Symposium</u> , 2000. <u>Proceedings. 18th IEEE</u> , 30 April-4 May 2000, (2000), 73-78	
		LIANG, HUA-GUO , et al., "Two-Dimensional Test Data Compression for Scan-Based Deterministic Bist", <u>Proceedings International Test Conference 2001</u> , (2001), 894-902	
		TOUBA, NUR A., et al., "Transformed Pseudo-Random Patterns for BIST", <u>Proceedings 13th IEEE VLSI Test Symposium</u> , (1995), 410-16	
		TREYTNAR, DIETER , et al., "LFSR Test Pattern Crosstalk in Nanometer Technologies", <u>IEEE Workshop on Signal Propagation on Interconnects</u> , Pisa, Italy, (May 12-15, 2002), 115-118	

EXAMINER**DATE CONSIDERED**

Substitute Disclosure Statement Form (PTO-1449)

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached